

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/814,505	KEYS ET AL.
	Examiner	Art Unit
	Christopher B. Shin	2181

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
710	313, 315	12/10/2006	CBS
710	56, 72	12/10/2006	CBS
709	230	12/10/2006	CBS

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
PALM (INVENTOR FOR DOUBLE PATENTING)	8/1/2006	CBS
EAST (EPO, USPAT, US-PGPUB, JPO, DERWENT IBMTDB,USOCR)	8/2/2006	CBS
PLUS	12/9/2006	CBS